

Form PTO 1449 Rev. 7-80	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No. PO8734/BTS054034	Serial No. 10/565,909
LIST OF PRIOR ART CITED BY APPLICANT (Use Several Sheets If Necessary)		Applicant Markus Haiml et al	
		Filing Date January 25, 2006	Group No. 2877

## U.S. PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/FLE/	AA	**4,245,800	01/20/81	Henderson	244	3.13	
	AB	**5,034,613	07/23/91	Denk et al	250	458.1	
	AC	5,445,934	08/29/95	Fodor et al	435	6	
	AD	**5,459,574	10/17/95	Lee et al	356	437	
	AE	5,742,355	04/21/98	(Bel. to corresp. to WO 96/15625) De Haan et al	348	607	
	AF	5,822,472	10/13/98	(Bel. to corresp. to WO 95/33108) Danielzik et al	385	12	
	AG	5,959,292	09/28/99	(Bel. to corresp. to WO 95/33108) Duveneck et al	250	227.11	
	AH	6,078,705	06/20/00	(Bel. to corresp. to WO 98/35940) Neuschäfer et al	385	12	
	AI	6,122,016	09/19/00	(Bel. to corresp. to WO 96/15625) De Haan et al	348	620	
	AJ	6,198,869 B1	03/06/01	(Bel. to corresp. to WO 98/22799) Kraus et al	385	129	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
/FLE/	AL	95/33197 A1	12/07/95	World				
	AM	01/13096 A1	02/22/01	World				X
	AN	02/46756 A1	06/13/02	World				X
	AO	**00/71028	11/30/00	World				
/FLE/	AP	**02/054071	07/11/02	World				

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/FLE/	AR	Science, 248, April 6, 1990, pages 73-76, Winfried Denk et al, "Two-Photon Laser Scanning Fluorescence Microscopy"
/FLE/	AS	Applied Physics, B, 73 (month unavailable) 1990, pages 869-871, G.L. Duveneck et al, "Evanescent-field-induced two-photon fluorescence: excitation of macroscopic areas of planar waveguides"
/FLE/	AT	Analytica Chimica Acta, 469, (month unavailable) 2002, pages 49-61, Gert L. Duveneck et al, "Planar waveguides for ultra-high sensitivity of the analysis of nucleic acids"

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	AB	6,437,345 B1	08/20/02	(Bel. to corresp. to WO 99/50960) Bruno-Raimondi et al	250	458.1	
	AC	6,510,263 B1	01/21/03	(Bel. to corresp. to WO 01/55691) Maisenhoelder et al	385	37	
	AD	6,873,764 B2	03/29/05	(Bel. to corresp. to WO 01/55691) Maisenhoelder et al	385	37	
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	AF	7,060,957 B2	06/13/06	(Bel. to corresp. to WO 01/84182) Lange et al	250	208.1	
	AG	2001/0001021 A1	05/10/01	(Bel. to corresp. to WO 98/22799) Kraus et al	385	12	
	AH	2002/0076154 A1	06/20/02	(Bel. to corresp. to WO 01/55691) Maisenhoelder et al	385	37	
	AI	2002/0182631 A1	12/05/02	(Bel. to corresp. to WO 01/48875) Schumann-Mader et al	435	6	
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/FLE/	AS	IEEE Journal of Quantum Electronics, Vol. 31, No. 9, September 1995, pages 1705-1708, T. Spirig et al, "The Lock-In CCD-Two-Dimensional Synchronous Detection of Light"
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	AB	2003/0186914 A1	10/02/03	(Bel. to corresp. to WO 02/20879) Hofer et al	514	44	
	AC	2004/0008394 A1	01/15/04	(Bel. to corresp. to WO 01/94182) Lange et al	359	237	
	AD	2004/0038386 A1	02/26/04	(Bel. to corresp. to WO 00/04149) Zesch et al	435	287.2	
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/FLE/	AR	J. Opt. Soc. Am. A, Vol. 18, No. 8, August 2001, pages 1972-1979, Arnaud Dubois, "Phase-map measurements by interferometry with sinusoidal phase modulation and four integrating buckets"
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/FLE/	AT	***"High-resolution full-field optical coherence tomography with a Linnik microscope"
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		Proceedings of the Spie - The International Society for Optical Engineering Spie-Int. Soc. Opt. Eng. USA, Bd. 4633, 23 Januar 2002 (2002-01-23) Seiten 50-61, XP001203516

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